



Denver X-ray Conference 2019

5 – 9 August 2019 | Lombard, Illinois, USA

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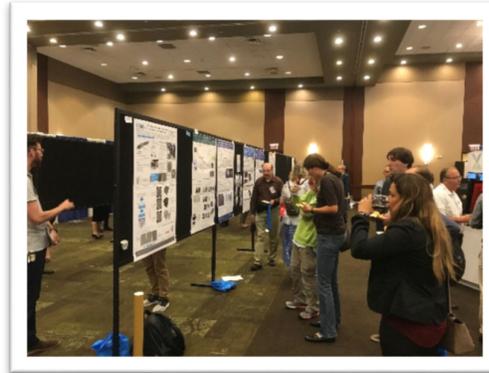
The 68th annual Denver X-ray Conference (DXC) was held as a joint meeting with the 25th International Congress on X-ray Optics and Microanalysis (ICXOM-25) from August 5 - 9 in Lombard, Illinois, USA. Located about 30 km southwest of the Chicago O'Hare Airport, Chicago's modern skyline and skyscrapers could be clearly seen from the conference hotel.

Held annually in the U.S., DXC is the world's largest X-ray conference. Almost 400 experts from both academia and industry attended DXC this year and discussed many topics, including general XRD, stress/texture/in-situ, SAXS, PDF, Rietveld, XRF (both WDXRF and EDXRF), handheld devices, microscopy, hardware (instruments and detectors), and analysis software.

Workshops and evening poster sessions were held during the first two days of the conference. Five Rigaku employees (three from Rigaku Americas, two from Japan) were invited to participate as workshop instructors, covering topics such as X-ray computed tomography, XRD sample preparation, and quantitative and trace XRF analysis.



Rigaku held a luncheon seminar to introduce unique techniques and analysis methods available with our analytical equipment, including the nano3DX, CT Lab HX and CT Lab GX X-ray computed tomography instruments, the ZSX Primus IV sequential XRF spectrometer, and the Direct Derivation (DD) method for quantification by XRD. We appreciate the numerous people who attended our seminar.



At the poster sessions, Rigaku presented the results of experiments on operand measurement of battery cells using the SmartLab diffractometer with a new battery cell attachment, and introduced an ultra-high-speed hybrid pixel array detector. Posters also discussed state-of-the-art texture analysis using SmartLab Studio II, local structure analysis of non-crystalline materials based on PDFs, and analysis of crystalline phases and elements in fly and bottom ashes using the MiniFlex benchtop XRD diffractometer and NANOHUNTER II benchtop TXRF spectrometer.

Congratulations to all the Best Poster Award winners, including the Best XRF Poster, awarded to Kyoto University for “Measurement of Continuous X-ray Polarization by 3D-printed Instrument,” and the Best XRD Poster, awarded to Cranfield University for “Characterization of Synthetic and Biogenic Hydroxyapatite Using Modern Synchrotron Pair Distribution Function Techniques,” and Industrial University of Santander for “Structure and Hirshfeld Surface analysis of a new structure of oxymetazoline chloride.”

At the oral sessions, Rigaku presented the benchtop CT Lab HX, an X-ray CT scanner with the most powerful X-ray source and versatile, microbeam applications using a newly developed X-ray optic: CBO- μ , accurate GISAXS analysis for nano-devices using a two-dimensional detector, accurate oil analysis by XRF with matrix correction methods, and quantitative phase analysis on model-free whole-powder-pattern fitting by the direct derivation method.

Thanks to everybody who attended the conference, especially to all who visited our booths, attended the “Lunch and Learn” and showed interest in our presentations. We hope to see you again at next year’s conference in Bethesda, MD.